

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

Claims 1-13 (Canceled)

Claim 14 (Original): A system comprising:

a tester to apply one or more tests to a device; and
logic, communicatively coupled to the tester, to enable one or more resources of the tester according to one or more properties of an electronic license and to create at least one log file having resource use information for one or more tests executed on the tester.

Claim 15 (Original): The system of claim 14, wherein the logic is to enable an amount of memory available on the tester according to one of the properties of the electronic license.

Claim 16 (Original): The system of claim 14, wherein the logic is to enable a speed available on the tester according to one of the properties of the electronic license.

Claim 17 (Original): The system of claim 14, wherein the logic is to enable a number of waveforms available on the tester according to one of the properties of the electronic license.

Claim 18 (Original): The system of claim 14, wherein the logic is to enable a number of edge transitions available on the tester according to one of the properties of the electronic license.

Claim 19 (Original): The system of claim 14, wherein the tester comprises a system-on-a-chip (SOC) tester.

Claim 20 (New): The system of claim 14, wherein the at least one log file having resource use information for one or more tests executed on the tester comprises at least one log file having resource use information for one or more tests executed on the device tester using the electronic license.

Claim 21 (New): The system of claim 14, wherein the resource use information comprises information on an amount of time the tester is used.

Claim 22 (New): The system of claim 14, wherein the resource use information comprises information on an amount of memory used by the tester during testing of the device.

Claim 23 (New): The system of claim 22, wherein the information on the amount of memory used by the tester during testing of the device is a maximum amount of memory used by the tester over a predefined period of time.

Claim 24 (New): The system of claim 14, wherein the resource use information comprises information on a speed at which tests are executed by the tester.

Claim 25 (New): The system of claim 14, wherein the logic is to generate a usage report based on the at least one log file.